


<b>Search Notes</b>  	<b>Application/Control No.</b>  10574489	<b>Applicant(s)/Patent Under Reexamination</b>  FUNAKOSHI ET AL.
	<b>Examiner</b>  KENDRA D CARTER	<b>Art Unit</b>  1617

SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor search (eDAN, PALM)	9/29/09	KDC
STN (search included)	9/29/09	KDC
EAST	10/05/09	KDC

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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